Search Notes

| Application/Control No. | Applio Reexa |
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| 10/699.613 | DELE |

Examiner

Phallaka Kik

Applicant(s)/Patent under Reexamination DELEULE, ARNAUD Art Unit

2825

| SEARCHED | | | | | |
|----------|----------|-----------|----------|--|--|
| Class | Subclass | Date | Examiner | | |
| 716 | 10,19 | 11/1/2005 | PK | | |
| 700 | 116,221 | 11/1/2005 | PK | | |
| 700 | 225 | 11/1/2005 | PK | | |
| 326 | 38,41,47 | 11/1/2005 | PK | | |
| 326 | 101 | 11/1/2005 | PK | | |
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| INTERFERENCE SEARCHED | | | | |
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| SEARCH NOT (INCLUDING SEARCH | |) |
|---|-----------|------|
| | DATE | EXMR |
| BRS (EAST)USPAT, USPGPUB Cls/Sub searched: 716/1-21; 700/115- 116,221-222,224-227; 326/38-50,101- 103; 438/6-10 (see attach) | 11/1/2005 | PK |
| EPO, JPO, IBM TDB, Derwent (see attached) | 11/1/2005 | PK |
| IEE/IEEE Xplore (see attached) | 11/1/2005 | PK |
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